

# OSICS BKR

## Variable Back Reflector

The OSICS BKR module integrates a variable reflector that can be set from 3 to 55 dB and operates throughout a large wavelength range.

The OSICS BKR emulates reflectance that normally occurs from all optical interfaces within fiber optic systems.

It is the perfect tool in R&D to test transponder prototypes and see how their operation is affected by undesired back reflection. It could also be used in large PON/WDM test-bed to stress transmitters and receivers in the system.

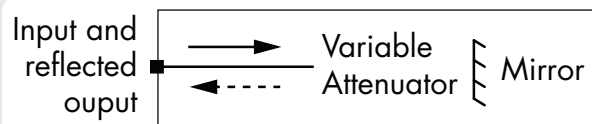
### Specifications

	OSICS BKR
Wavelength Range	1250–1650 nm on SMF 1240–1520 nm on PMF
Reflectance Range	Up to 55 dB
Calibrated Range	Up to 40 dB at 1310 and 1550 nm
Reflectance Accuracy (typ.)*1	±0.3 dB
Insertion Loss	≤ 4 dB (3 dB typ.)
Reflection Setting Resolution*2	0.02 dB
Polarization Dependent Loss	0.2 dB
Speed	0.1 second / 3 dB (typ.)
Maximum Input Power	0.2 W (+23 dBm)
Optical Connectors	FC-APC on SMF-28 FC-APC on PMF PM13

All specifications are tested at 23°C +/- 2°C; optical connector included.

\*1: Inside calibrated range and up to 35 dB.

\*2: From 1 to 10 dB; 0.1 dB for 10 to 40 dB.



OSICS BKR Module Principle

### Key Features

- **55 dB Reflection Range with 0.1 dB Resolution**

The large reflection range capability allows to adapt to any set-up with a single instrument.

- **Real-time and Easy Operation**

The platform user-friendly interface allows real-time adjustment of the reflectance. Each module reflectance can be read at any time on the OSICS front panel display.

- **Single-slot Module Inside the OSICS Platform**

You will benefit from all OSICS platform capabilities: remote commands, ability to host up to 8 modules including DFBs, high performance tunable laser sources, optical switches, etc.



### Applications

- **Simulation of cumulated reflection from unmated connectors (PON, WDM systems)**  
The large reflection range capability allows to adapt to any set-up with a single instrument.
- **Component testing (transmitters, receivers, laser diode, isolator, ...)**  
Used with a bit-error-rate tester, it allows testing return loss sensitivity of individual components.
- **Laser development and production**
- **OTDR testing**

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